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Erratum: Big data and deep data in scanning and electron microscopies: deriving functionality from multidimensional data sets

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After publication of this study [1], we found that Anton Ievlev was not listed among the authors. This error has now been corrected and the full list of authors contributing to this work is included. The Reference [119] has also been updated. The correct information is given below: A.V. Ievlev, S.V. Kalinin, Data encoding based on the shape of the ferroelectric domains produced by using a scanning probe microscope tip, Nanoscale (2015), doi:10.1039/c5nr02443a.

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